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## 779A TOOL 25-BIT PLUG-IN MATCHER METHOD OF OPERATION AND TESTS NO. 1 ELECTRONIC SWITCHING SYSTEM

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		CONTENTS PAGE
ł	1.	GENERAL 1
	2.	APPARATUS 4
	3.	METHOD OF OPERATION 5
	/	OBTAINING EXPECTED RESULTS 5
		SETTING UP AND OPERATING THE BIT
		MATCHER 6
		ANALYZING EXPERIMENTAL RESULTS . 8
		SPECIFIC EXAMPLE USING THE BIT MATCHER
		8
<b>`</b> .	4.	TESTING THE BIT MATCHERS 11
		MATCH ON ZERO TEST
		MATCH ON ONE TEST

----

#### FIGURES

۱.	779A Tool 25-Bit Plug-In Matcher	. 2
2.	779A Tool 25-Bit Plug-In Matcher (Example Location on CC)	3
3.	Oscilloscope Representation of Sync Pulse and Gating Pulse	5
4.	Connecting Diagram for 779A Tool 25-Bit Plug-In Matcher and Dual Trace Oscilloscope	6
5.	Matchers Used for Logical AND Gate of Match Condition	7

	CONTENTS PAGE						
6, S	ample Program Loop 9						
7. Conversion from Octal (Program Address) to Binary (Switch Positions)							
8. S	implified View of CC Y Register 12						
1. GENERAL							
1.01 This section describes the procedure for using the 779A tool 25-bit plug-in matcher (bit matcher) in 2-wire and 4-wire No. 1 Electronic Switching Systems (ESS).							
1.02	This section is reissued for the following reasons:						
(a)	To add $\emptyset$ FL-M $\emptyset$ DE-05 in paragraph 4.02 (7) and (14).						
(b)	To make minor changes.						
(c)	To delete reference to No. 1 ESS ADF.						
1.03 The bit matcher (Fig. 1) is a manual testing tool. It is used with an oscilloscope to diagnose hardware faults not located by the maintenance program in the system.							
1.04 The set the ti regist contro contes	The bit matcher contains 25 toggle switches and one reset (RST) button (Fig. 1 and 2). elf-contained bit matcher is used to determine ime at which the contents of a flip-flop or er in any logic frame [for example, central ol (CC)] reaches a predetermined state. The nts of any register or flip-flop are matched						

against the state set up manually on its 25 toggle switches. A sync pulse and a match indication

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Fig. 1-779A Tool 25-Bit Plug-In Matcher

(lighting of the RST lamp) are generated when a match occurs.

1.05 Toggle s' /itches 0 through 24 represent 25 bits of information-present on the test connector input pins 0 through 11 and 15 through 27. Each bit can be matched to one of three conditions selected by the switches on the front panel of the bit matcher: one (up), zero (down), or don't care (center). When the 24 bits of information coming into the bit matcher correspond to the setting of the 24 toggle switches, the RST lamp lights. In addition, when the preset conditions are met, a sync pulse is available at the sync pulse output coaxial connector on the bottom of the bit matcher. The sync pulse will be present for the duration of the match condition.

1.06 The bit matcher plugs into test connectors on the front of the logic frame (Fig. 2). These test connectors normally have access to the zero side of all registers and flip-flops in the logic frame. The bit matcher is most commonly used for troubleshooting with the CC PAR (CC test position 124-27; see SD-1A105-1, B85, C1) and the dn't-care position.

CC index adder output register (IAOR) (CC test position 114-13; see SD-1A105-1, B74, H1) test connectors. The PAR test connector (124-27) is provided with one-half microsecond clock signals on pin 27 (6T8) and or pin 26 (14T16) to permit the match condition to be sampled.

By sampling the match condition at either 1.07

6T8 or 14T16, the possibility of developing a false match condition during the time that the PAR is changing is eliminated. Normally, the 6T8 clock pulse (key 24) should be used. It should be noted that key 24 is set to zero rather than one to provide the 6T8 sample pulse. This is necessary because the PAR test connector pins 26 and 27 are high rather than low when the clock signal is present.

- 1.08 To match a program store address, the bit matcher keys should be set up as follows:
  - (a) Key 24 should be set to zero.
  - (b) Keys 23 through 20 should be set to the



Fig. 2—779A Tool 25-Bit Plug-In Matcher (Example Location on CC)

by contacting the output of the first matcher to

(c) Keys 19 through 0 should be set to the desired address.

1.09 The IAOR test connector (114-13) is similarly provided with one-half microsecond clock signals on pin 27 (18T20) and on pin 26 (0T2) to permit the match condition to be sampled. Normally, the 18T20 clock pulse (key 24) should be used. Thus, to match on a call store address, the bit matcher keys should be set up as follows.

- (a) Key 24 should be set to zero.
- (b) Keys 23 through 18 should be set to the don't-care position.
- (c) Keys 17 through 0 should be set to the desired address.

It should be noted that a match will occur when the contents of the IAOR equal the setting of the keys on the matcher even if the contents of the IAOR are used for data rather than a call store address.

1.10 Listings of other registers and flip-flops and their associated test connector numbers are located in the apparatus indexes of the various frame SDs (for example, SD-1A105-01 for CC).

1.11 A dual trace oscilloscope connected to the bit matchers by a 50-ohm coaxial cable is used to display two individual pulses: a sync pulse and a gating pulse. The sync pulse (Fig. 3), displayed on the oscilloscope, is obtained by connecting the EXT SYNC and the Y input of channel A of the oscilloscope to the 25-bit plug-in matcher (Fig. 4). The gating pulse is obtained by using channel B of the oscilloscope and probing specific logic frame register or flip-flop leads on the back of the frame. The length of time that the gate is open, represented by the width of the gating pulse, represents the length of time that the register or flip-flop can transfer data. This visual representation also exhibits the time at which the gating pulse should come-up (the leading edge of the gating pulse in relation to the sync pulse). The test results should be compared to expected results obtained from interpretation of source material.

1.12 When desired, the output of one matcher can be used as the input to another matcher by connecting the output of the first matcher to an **unused** input pin on a second matcher. A logical AND of the matcher condition of two or more matchers can, thereby, be developed. For example, if a sync pulse is needed when a particular data pattern is written at a specific location in call store, the configuration shown in Fig. 5 can be used. Matcher one is set up as previously described for a call store address match except that the 0T2 clock pulse (key 23) is used to sample the matcher instead of the 18T20 clock (key 24). The 0T2 clock is used because the buffer register does not receive the data to be written into call store until T0 on register to memory instructions.

- **1.13** Reference may need to be made to the bit matcher schematic SD-1A298-01.
- 1.14 The following abbreviations are used in this section:

CC	Central Control
ESS	Electronic Switching System
IAOR	Index Adder Output Register
OLCP	Off-Line Card Program
PC	Program Control
PS	Program Store
RST	Reset
TLM	Trouble Locating Manual

#### 2. APPARATUS

- **2.01** The following apparatus is needed in this procedure:
  - (a) One 779A tool 25-bit plug-in matcher
  - (b) An E09-180A oscilloscope kit with an 1801A dual channel vertical amplifier, or equivalent, and a 10005A voltage probe and 10-foot cable that is part of the kit

(c) One 50-ohm coaxial cable (RG 58/U or RG 58/UA) 8 feet long terminated on each end with a UG-88 B/U male connector

(d) One T connector (UG-274 B/U).



#### Fig. 3—Oscilloscope Representation of Sync Pulse and Gating Pulse

#### 3. METHOD OF OPERATION

3.01 There are a number of ways to use the bit matcher. The general procedure can be divided into three parts: obtaining expected results from source material, setting up and operating the bit matcher, and analyzing experimental results. Certain other operations have to be performed in the procedure to supplement the operation of the bit matcher, such as removing and restoring the frame power and placing the frame in an off-line configuration. A specific example for using the bit matcher is given in paragraph 3.09.

**3.02** This procedure does not attempt to explain how troubleshooting should be carried out. These techniques are left up to the individual office.

#### **OBTAINING EXPECTED RESULTS**

**3.03** Information that is needed for setting up and operating the bit matcher and for making a comparative analysis with experimental

results may be obtained from the following source material:

- SD and CD for the faulty frame
- Generic Program Map PK-1A002 (2-wire) and PK-2A002 (4-wire)
- Section 231-117-301 (2-wire) or 231-417-301 (4-wire) (Off-Line Operations)
- Diagnostic program documents (PD and PF) for the specified frame.

Any other source material may be used, if needed, to supplement office troubleshooting techniques.

- **3.04** The following data or information must be obtained before using the bit matcher:
  - (a) The frame that is faulty
  - (b) The register or flip-flop and associated terminal leads to be probed



Fig. 4—Connecting Diagram for 779A Tool 25-Bit Plug-In Matcher and Dual Trace Oscilloscope

- (c) The test connector location that accesses the specified register or flip-flop (the PAR and IAOR test connectors in the CC are used most commonly)
- (d) The time at which a sync pulse and gating pulse occur when a specific lead is to be probed
- (e) A series of program addresses that use the specific register or flip-flop being tested
- (f) The lower and upper program address limits that can be used in a program loop
- (g) The program address that is to be matched (address set up on the bit matcher switches)
- (h) The program store, program store bus, call store, and call store bus to be put in off-line configuration.

#### SETTING UP AND OPERATING THE BIT MATCHER

- **3.05** Use the following general procedure for the bit matcher.
  - Remove faulty frame from service and then remove frame power. For the procedure to take the equipment out of service, refer to the following sections:
    - (a) Section 231-405-302 in 4-wire No. 1 ESS offices.
  - (b) Section 231-105-302 in 2-wire No. 1 ESS offices.
  - (2) Plug bit matcher into proper frame test connector as determined from information listed in paragraph 3.03.

Caution: Do not insert or remove bit matcher when frame power is on.



Fig. 5—Matchers Used for Logical AND Gate of Match Condition

- (3) Restore frame power by using procedures in the sections listed in (1).
- (4) Set standby (faulty) frame in off-line configuration. Refer to Section 231-117-301
  (2-Wire) or 231-417-301 (4-wire).
- (5) Set up program loop between two program store addresses. Refer to Section 231-117-301(2-wire) or 231-417-301 (4-wire).
- (6) Start off-line loop. Refer to Section 231-117-301
  (2-wire) or 231-417-301 (4-wire).

(7) Set desired program address on bit matcher toggle switches.

**Note:** As the program passes through the program address that is set up on toggle switches of bit matcher, RST lamp lights. This switch (RST switch-lamp combination) must be operated before it indicates further matching.

(8) Connect channel A and EXT SYNC terminals of dual trace oscilloscope to sync pulse output connector on bit matcher using 50-ohm coaxial cable.

- (9) Connect a probe to channel B of dual trace oscilloscope.
- (10) Trigger oscilloscope so that sync pulse is displayed on oscilloscope screen.
- (11) Probe predetermined lead or terminals in the back of faulty or suspected frame.

#### ANALYZING EXPERIMENTAL RESULTS

- **3.06** Use the following procedure to analyze the signals displayed on the oscilloscope.
  - (1) Determine which pulse is the sync pulse. (Sync pulse is to be used as reference pulse.)

(2) Determine the time at which the sync pulse occurs by using the CD or SD for that specific register or flip-flop.

(3) Compare sync pulse to gating pulse as displayed on oscilloscope. Determine the following:

- Time duration of gating pulse
- Amplitude of gating pulse
- The time at which gating pulse occurs in relation to sync pulse

3.07 Compare test results to expected results obtained in 3.04. If any discrepancies occur, troubleshoot the equipment and make corrections. The procedure for using the bit matcher may be repeated until the fault has been located and repaired.

- **3.08** Restore system to normal operation by using the following procedure.
  - Remove frame from off-line operation. Refer to Section 231-117-301 (2-wire) or 231-417-301 (4-wire).
  - (2) Request system to diagnose faulty frame. (Refer to input message manual for diagnostic message for specified frame.)
  - (3) Remove frame power by using procedures in the sections listed in paragraph 3.05(1).
  - (4) Remove bit matcher from frame test position.
  - (5) Restore frame power and return frame to service by using the procedures in the sections listed in paragraph 3.05(1).

#### SPECIFIC EXAMPLE USING THE BIT MATCHER

3.09 This example is used to illustrate one specific use for the bit matcher. A program store (PS) test card is written to accomplish specific operations in the system registers (Fig. 6). Refer to Section 231-104-302 (2-wire) or 231-404-301 (4-wire). This PS test card is located in PS 0 at PS location MOD 1, pass 0, card 73 (1027300) since it is part of the off-line card program (OLCP). The following procedure for using the bit matcher is used.

(1) Remove the standby CC from service by typing in

#### CC-REMØVE-.

If the system response is  $\emptyset K$  and the OS lamp on the frame is lighted, power can be removed from the standby CC.

- (2) Remove power from the CC by using the following sequence.
  - (a) Operate FRAME CONTROL-REQ INH (request inhibit) key on CC control panel.
     ØFF NØR and ØS lamps light.

Caution: In 2-wire ESS do not depress the OFF key until the system prints ØK to RMV PWR.

PROGRAM L		DGRAM STO DRESS	RS		
<b></b>	1027300	00000	00000003	尼尼	3
	1027301	00710	00000001	wy	1
	1027302	00700	00000001	wy	± 1
	1027303	00730	00000001	WZ	1
	1027804	00790	00000001	WI.	1
	1027805	00750	377777777	WK	1
	1027306	00699	00000000	WF	0
	1027307	00722	000000000	W.I.	0 0
1	1027810	00600	00000000	WB	0
	1027311	05750	00000000	ww	0.8
	1027319	00005	20000001	и И	1
	1097313	0.4710	00000000	ww	1 0 M
	1027314	01600	00000001	100	1.12
	1097915	11490	00000007	CWD	1.D 07/0
	1027816	00035	21025211	TCIF	a (132 17527911
	1027817	06750	00000000	WW	0.1024014
	1027320	00005	20000000	ил Ч	1
	1027321	0.4700	00000000	WV	0 <b>V</b>
	1005000	00000	00000000	** 4	U, <b>N</b>
	1027322	08722	000000001	W.J	1,
	1021020	10400	00000027	CWR	27,0
	1007905	000000	A1021310 00000000	TULP	1027310
	1007000	00008	00000000	WK	0,2
	1027947	00000	20000001	11	1
	1021021	1/4 ( 00 00800	00000000	WZ WE	0,K
	1007991	10490	00000001	WF CIUD	1,1
	1007990	18400	010000027		27.F 10078007
	1007899	00754	81981001 97777777	1 CLF	102(00)
	1027394	00005	90000001	11	- 9111111111111111111111111111111111111
	1027335	04790	00000001	11	
	1027336	000021	91097906	W L	1007202
	1027337	00000	01027240	NVC NVC	1027300
·	1027340	00000	00000000	DAU RP	1027040
	1027341	00000	01097949	EVEN V.V.C	1/10/20 4-0
	1027342	00000	00000000	FAL	1021042
	1027848	000002	01097944	EVC	10279 (4
	1027844	00000	000000000	FR	1021044
	1027345	00002	01027316	FYC	1027946
	1027346	00000	00000000	FF	021090
	1627347	00002	01027350	EXC	1027350
	1027350	00000	00000000	EE	0
	1027351	00002	01027352	EXC	1027352
	1027352	00000	00000000	EE	0
	1027353	00002	01027354	EXC	1027354
	1027354	00000	00000000	EE	0
1	1027355	00002	01027356	EXC	1027356
	1027356	00000	00000000	EE	0
	1027357	00002	01027360	$\mathbf{EXC}$	1027360
	1027360	00000	00000000	EE	0

(CONTINUED)					
	1027361	00002	01027362	EXC	1027362
	1027362	00000	00000000	EE	0
ļ	1027363	00002	01027364	EXC	1027364
	1027364	00000	00000000	EE	0
	1027365	00002	01027366	EXC	1027366
	1027366	00000	00000000	EE	0
	1027367	00002	01027370	EXC	1027370
	1027370	00000	00000000	EE	0
	1027371	00002	01027372	EXC	1027372
	1027372	00000	00000000	EE	0
(	1027373	00002	01027374	EXC	1027374
	1027374	00000	00000000	EE	0
	1027375	00002	01027376	EXC	1027376
	1027376	00000	00000000	EE	0
	1027377	00010	01027300	Т	1027300

END OF PROGRAM

### Fig. 6—Sample Program Loop

- (b) Operate OFF key to remove power. PWR-OFF lamp lights.
- (3) Plug bit matcher into the standby CC test connector location 124-27 (PAR).

Caution: Do not insert or remove bit matcher when CC frame power is on.

- (4) Restore CC frame power by using the following sequence.
  - (a) Operate FRAME CONTROL-REQ INH key.
  - (b) Operate NOR key. OFF NOR lamp extinguishes.
  - (c) Momentarily operate ST key. PWR OFF lamp extinguishes.
  - (d) Momentarily operate CLK ST key.
- (5) Set the standby CC in off-line configuration by typing in

ØFL-CØNFIG-00 0 00 0. (CC offices and 4-wire ESS)

ØFL-CØNFIG-00 0 00 0 99 0. ((SP offices)

(6) Have standby CC repeatedly execute a program (Fig. 5) by typing in

ØFL-EXEC-03 0...0.(16 0s)

(7) Set up specified program address (underlined PS address in Fig. 6) on toggle switches of bit matcher as shown in Fig. 7.

(8) Connect channel A of a dual trace oscilloscope to sync pulse output connector of bit matcher via 50-ohm coaxial cable (Fig. 4). Use this same signal to trigger oscilloscope by connecting it into EXT SYNC terminal of oscilloscope.

- (9) Connect a probe to channel B of oscilloscope.
- (10) Probe MBYR1A lead terminal in the back of CC frame as shown in Fig. 8.
- (11) Analyze results displayed on oscilloscope. The following conclusions can be made.

- (a) Sync pulse is at time 6T8 (obtained from SD- and CD-1A105-01).
- (b) Gating pulse takes place at time 0T6.
- (c) Gating pulse occurs every 11 milliseconds.
- (12) Compare test results with expected results obtained from SD- and CD-1A105-01.
- (13) Remove CC from off-line operations by using the following sequence.
  - (a) Type in

#### ØFL-MØDE-02.

(b) Type in

#### ØFL-MØDE-03.

(c) Type in

CS-RESTØRE-C S 00. (2-wire)

CS-RESTØRE-S 00. (4-wire)

- (d) Type in
- CS-RESTØRE-C B 00. (2-wire)

CS-RESTØRE-B 00. (4-wire)

(e) Type in

#### CS-RESTØRE-S 00.

(14) Request system to diagnose standby CC by typing in

#### CC-DGN-CCR.

If system response ATP occurs, power can be removed from the unit.

- (15) Remove power from CC. [Refer to paragraph 3.09 (2).]
- (16) Remove bit matcher from test position.
- (17) Restore power to the standby CC. [Refer to paragraph 3.09 (4).]

(18) Standby CC restored to service and verified by ATP response.

#### 4. TESTING THE BIT MATCHER

**4.01** Office hardware faults which require the use of the bit matcher tool for diagnosis occur infrequently. Therefore, it is recommended that the tool be tested periodically to assure its operation and availability when the need does occur. The recommended test interval is at least every 6 months, or at any time when the tool may be suspected for any reason. Care should be exercised in storing and handling the tool to prevent any physical damage.

**4.02** Much of the procedure described in paragraph 3.09 is similar to that which is used to test the bit matcher. The off-line facility is set up to test each bit of the bit matcher for the following conditions:

- (a) Match on one
- (b) Match on zero
- (c) Don't care.

The example described in paragraph 3.09 uses the bit matcher and a specific program address to verify that the sync pulse is generated upon a match condition. In the following test, the sync pulse generation is assumed operating with the RST lamp used as the visual indicator of a match condition for each bit.

(1) Remove standby CC from service by typing in

#### CC-REMØVE-.

If the system response is  $\emptyset K$  and the OS lamp on the frame is lighted, power can be removed from the standby CC.

- (2) Remove power from the CC by using the following sequence.
  - (a) Operate FRAME CONTROL-REQ INH (request inhibit) key on CC control panel.
     OFF NOR and OS lamps light.

#### Caution: In 2-wire ESS do not depress the OFF key until the system prints ØK TØ RMV PWR.

- (b) Operate OFF key to remove power. PWR OFF lamp lights.
- (3) Plug bit matcher into standby CC test connector location 218-11 (XR).

# Caution: Do not insert or remove bit matcher when CC frame power is on.

- (4) Restore CC frame power by using the following sequence.
  - (a) Operate FRAME CONTROL-REQ INH key.
  - (b) Operate NOR key. OFF NOR lamp extinguishes.
  - (c) Momentarily operate ST key. When ST key is operated, PWR OFF lamp extinguishes.
  - (d) Momentarily operate CLK ST key.
- (5) Set up off-line configuration by typing in

ØFL-CØNFIG-00 0 00 0. (CC Offices)

✓ ØFL-CØNFIG-00 0 00 0 99 0. (SP Offices)

ØL01 ØK response.

#### MATCH ON ZERO TEST

- (6) 2-Wire ESS only: Set up program control (PC) keys at MCC to all zeros by releasing pushbuttons at positions zero through 22. BLCK (block) key should be released and remain released throughout the entire test procedure. Later, when all ones are entered into the PC keys and if the BLCK key is depressed, maintenance printouts will be inhibited.
  - (7) **2-Wire ESS:** Set up off-line program by typing in

+7

#### ØFL-MØDE-05

ØFL-EXEC-09 00010000 00010000.







Fig. 8—Simplified View of CC Y Register

Contents of PC keys will be written into CS 0 at address 10,000 every cycle.

4-Wire ESS: Set up off-line program by typing in

ØFL-MØDE-05.

ØFL-EXEC-10 00010000 00010000.

 (8) 2-Wire ESS and 4-Wire ESS: Place all toggle switches on the matcher tool in the don't-care position. Operate the RST lamp/switch. RST lamp should remain on.

1.1.1.

(9) Place toggle switch 0 in the one position. Operate RST. RST lamp should extinguish (mismatch).

(10) Place toggle switch 0 in the zero position. RST lamp should light (match). OperateRST. RST lamp should remain on. Leave toggleswitch 0 in the zero position.

(11) Repeat the test in Steps 9 and 10 individually for each toggle switch (1 through 22).
When in the one position, lamp should extinguish; when in the zero position, lamp should light.
After each test, switch is left in the zero position, eventually leading to an all zeros match.

Bits 23 and 24 toggle switches (23 and 24) are no-connects at the XR test connector location and, because of the tool's circuitry, will represent one inputs. If these positions are suspected of match-on-zero problems, pick a convenient 4.5 V point, such as an unused 4.5V load resistor (location 218-17, unused LR terminals 2 through 11) and apply it to the following XR test connector terminals in turn: (1) terminal 26 to test switch position 23 and (2) terminal 27 to test position 24.

#### MATCH ON ONE TEST

(12) Type in

∕ ØFL-MØDE-02.

This message stops the standby CC for next series of tests.

(13) 2-Wire ESS: Set up MCC PC keys to the all ones position by pushing keys down at bits 0 through 22. BLCK key should remain released.

(14) 2-Wire ESS: Type in

ØFL-MØDE-05.

✓ ØFL-EXEC-09 00010000 00010000.

Contents of PC keys, all ones, will be written into CS 0 at address 10,000 every cycle.

4-Wire ESS: Type in

ØFL-MØDE-05. ØFL-EXEC-09 00010000 00010000.

(15) 2-Wire ESS and 4-Wire ESS: Place all toggle switches of the matcher tool in the don't-care position, except for toggle switch 0, which should be left in the zero position. Operate RST. Lamp should extinguish (mismatch).

(16) Place toggle switch 0 in the one position; lamp should light (match). Leave toggle switch 0 in the one position.

(17) Repeat test for each toggle switch (1 through 24). Whenever in the zero position, the lamp should extinguish when RST is operated; whenever in the one position, the lamp should light and remain lighted before and after RST is operated. After each test, each switch should be left in the one position, which eventually leads to the all ones match.

4.03 The above test verifies each bit for the match-on-one, the match-on-zero, and the don't-care conditions. Now proceed to terminate the off-line mode and restore the system by following the sequence shown in paragraph 3.09, Steps 13 through 18. This entire test procedure requires approximately 15 minutes to complete.

**4.04** If the bit matcher tool fails any part of the above test, it should be sent, through normal forwarding procedures, to the WE repair control location for necessary repairs.

# GO TO PAGE 10 STEP 13 OF PAR. 3.09 FOR RESTORAL.

BELL SYSTEM PRACTICES AT&TCo Standard

## 779A TOOL 25-BIT PLUG-IN MATCHER METHOD OF OPERATION AND TESTS NO. 1 ELECTRONIC SWITCHING SYSTEM

#### 1. GENERAL

1.001 This addendum supplements Section 231-001-301, Issue 6 and replaces Issue 1 of this addendum. Place this pink sheet ahead of Page 1 of

the section and discard Issue 1 of this addendum.

**1.002** This addendum is reissued to correct TTY input messages for the match on one test in paragraph 4.02.

1.003 Issue 1 of this addendum was issued to correct ØFL-EXEC-09 and ØFL-EXEC-10 input messages in paragraph 4.02.

2. CHANGES TO SECTION

#### **ISSUE 1 CHANGES**

- 2.001 On Pages 11 and 12, change Step (7) to read as follows:
  - (7) **2-Wire ESS:** Set up off-line program by typing in

### ØFL-MØDE-05.

ØFL-EXEC-09 00010000 00010001.

Contents of PC keys will be written into CS 0 at address 10,000 every cycle.

4-Wire ESS: Set up off-line program by typing in

#### ØFL-MØDE-05. ØFL-EXEC-10 00010000 00010001.

- 2.002 On Page 13, change Step (14) to read as follows:
  - (14) **2-Wire ESS:** Type in

ØFL-MØDE-05.

ØFL-EXEC-09 00010000 00010001.

Contents of PC keys, all ones, will be written into CS 0 at address 10,000 every cycle.

4-Wire ESS: Type in

ØFL-MØDE-05. ØFL-EXEC-09.00010000 00010001.

#### **ISSUE 2 CHANGES**

**2.003** On Page 13, change step (14) to read as follows:

(14) **2-Wire ESS:** Type in

PS-RESTORE-SOO. CC-REMOVE-.ØK.

Power Cycle CC-(PS power restored)

Type in 00000 990

ØFL-CONFIG-0\_\_\_\_.PF ØFL-MØDE-05.ØK. ØFL-EXEC-09 00010000 000100001.ØK.

Contents of PC keys, all ones, will be written into CS 0 at address 10,000 of every cycle.

4-Wire ÊSS: Type in

ØFL-MØDE-05. ØFL-EXEC-09 00010000 000100001.

NOTICE

Not for use or disclosure outside the Bell System except under written agreement

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Page 1 1 Page